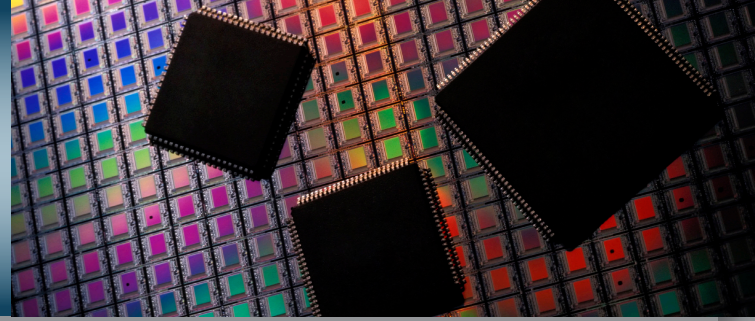


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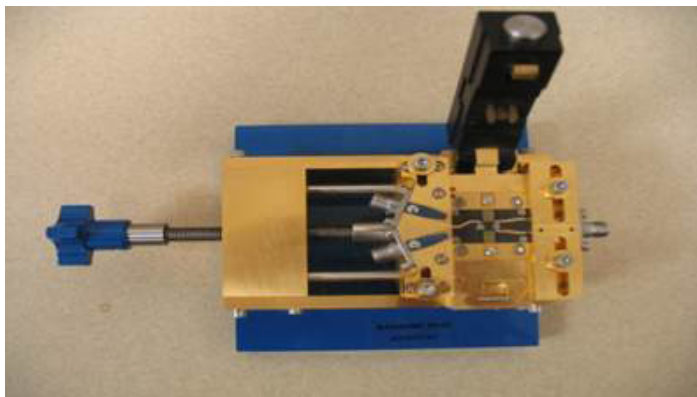
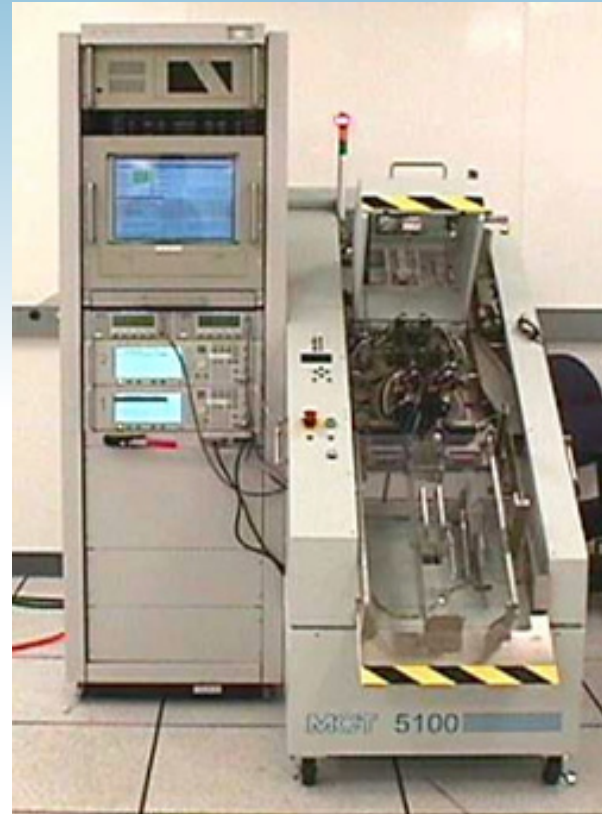
RF TEST SOLUTIONS - 50GHz & Up

Test Systems

- RF Test System (RFTs) *50GHz & Higher
- Credence- ASL3000 Expandable to 50GHz

RF Probe and Package Test 50GHz & Higher

- Membrane wafer probes that are capable of testing to 80GHz
- RF testing has included transceivers for military communication systems requiring full parametric testing for a flip chip application
- High speed analog tests involving RF to digital output of I & Q vectors
- The design of membrane is multi-layer circuit capable of providing impedance control signal paths to the DUT
- Wafer coax probing experience



Tests performed by Integra

- Noise Figure and IMD – Inter-modulation Distortion
- IP3 Third Order Intercept
- Return Loss (input and output)
- Gain and Phase
- Power Output
- Error Vector Magnitude (EVM)
- Operating and Standby Current
- 1db Compression Point
- S Parameters
- Basic bench measurable DC / RF measurements



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